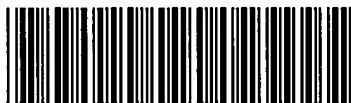


**Search Notes**

Application No.

09/545,288

Examiner

Minh Trinh

Applicant(s)

AYALA ET AL.

Art Unit

3729

**SEARCHED**

Class	Subclass	Date	Examiner
29	600, 825, 829, 827, 830, 846	1/18/2005	mt
235	492, 487,		
	380-385		
257	679, 728		
	992, 276		
343	866, 873		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East text, image and inventor name searched (see print out)	1/18/2005	mt
Reviewed 5,598,032 and 5,809,633 and all references cited therefrom.		

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under  
Reexamination  
AYALA ET AL.

Examiner

Minh Trinh

Art Unit

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Page 1 of 1

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	B	US-6,049,461	04-2000	Haghiri-Tehrani et al.	361/737
	C	US-5,208,450	05-1993	Uenishi et al.	235/492
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.